10/573996

### PATENT APPLICATION

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

IAPZORes'dFCTIFTO 30 MAR 2006

Makoto AOKI et al.

Application No.: New U.S. National Stage of

PCT/JP2005/004781

Filed: March 30, 2006 Docket No.: 127612

For: INFRASOUND ABSORBING STRUCTURE

# **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of one or more non-English language reference is discussed in the present specification. See References <u>2-4</u>.
- 3. One or more reference cited herein was cited in the International Search Report.
  An English language version of the International Search Report is attached for the Examiner's information. See References 5-16.
- 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 2-10 & 12-16.

# New U.S. National Stage of PCT/JP2005/004781

6. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See References 2-10, 12-14 & 16.

- 7. A partial English language translation of one or more Japanese Patent Publication cited herein has been obtained, and is attached, but has not been reviewed for accuracy. See Reference 11.
- 8. Reference 1 corresponds to reference 8.

Respectfully submitted,

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JAO:JSA/crh

Date: March 30, 2006

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE
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# 14P20 Rec 61 01,770 30 MAR 2006 Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127612		1 @	APPLICATION NO. New U.S. National Stage of 7 PC 1112003/004781	
INFORMATION DISCLOSURE STATEMENT						10	PCDJIP200	(\$/00\$784) 6
(Use several sheets if necessary)				APPLICANTS Makoto AOKI et al.				
				FILING DATE March 30, 2006				
U.S. PATENT DOCUMENTS								
Examiner Initials	Cite No.	Document Number	Date		Name			
	1	2002/0027997 A1	03/07/2002		WATANABE et al.			
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FOREIGN PATENT DOCUMENTS								
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	2	JP A 2001-032400	02/06/2001		JAPAN		х	х
	3	JP A 10-140700	05/26/1998		JAPAN		x	х
	4	JP A 2003-307467	10/31/2003		JAPAN		x	х
	5	JP A 2004-052274	02/19/2004		JAPAN		х	х
	6	JP A 07-168577	07/04/1995		JAPAN		x	х
	7	JP A 05-289673	11/05/1993		JAPAN		х	х
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	9	JP A 2001-306080	11/02/2001		JAPAN		х	. X
	10	JP A 2000-318696	11/21/2000		JAPAN		x	х
	11	JP A 58-47700 w/ partial translation	03/19/1983		JAPAN			
	12	JP A 08-006569	01/12/1996		JAPAN		х	х
	13	JP A 09-111906	04/28/1997		JAPAN		x	х
	14	JP A 11-351609	12/24/1999		JAPAN		х	х
	15	JP A 03-125704	05/29/19	991	JAPAN		x	
	16	JP A 2003-58168	02/28/20	003	JAPAN		x	х
			OTHER I	OOCUME	NTS			
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